

FDB8453LZ N-Channel PowerTrench[®] MOSFET 40V, 50A, 7.0m Ω

Features

- Max $r_{DS(on)} = 7.0 m\Omega$ at $V_{GS} = 10V$, $I_D = 17.6A$
- Max $r_{DS(on)} = 9.0m\Omega$ at $V_{GS} = 4.5V$, $I_D = 14.9A$
- HBM ESD protection level of 7.6kV typical (note 4)
- Fast Switching
- RoHS Compliant

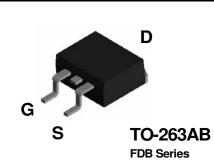


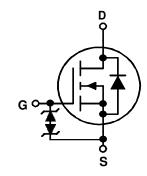
General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench[®] process that has been especially tailored to minimize the on-state resistance and switching loss. G-S zener has been added to enhance ESD voltage level.

Applications

- Inverter
- Power Supplies





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V _{DS}	Drain to Source Voltage			40	V	
V _{GS}	Gate to Source Voltage			±20	V	
I _D	Drain Current -Continuous (Package limited)	T _C = 25°C		50	74	
	-Continuous (Silicon limited)	T _C = 25°C		74		
	-Continuous	$T_A = 25^{\circ}C$	(Note 1a)	16.1	Α	
	-Pulsed			100		
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	253	mJ	
P _D	Power Dissipation	T _C = 25°C		66	14/	
	Power Dissipation	T _A = 25°C	(Note 1a)	3.1	W	
T _J , T _{STG}	Operating and Storage Junction Temperature R	ange		-55 to +150	°C	

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	1.88	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a	l) 40	0/10

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB8453LZ	FDB8453LZ	TO-263AB	330mm	24mm	800 units

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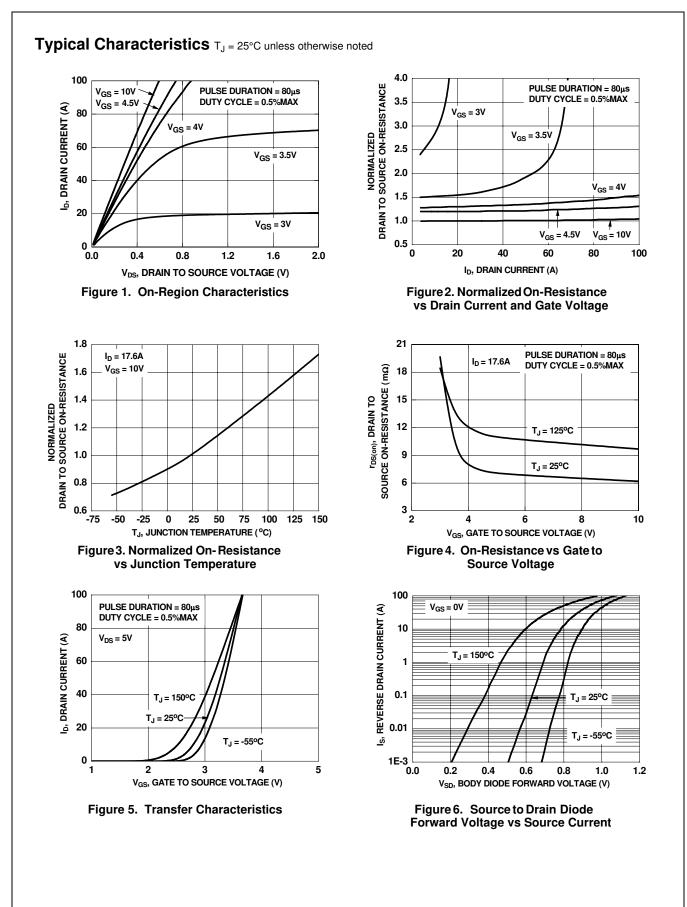
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics		1		1	1
BV _{DSS}	Drain to Source Breakdown Voltage	$I_{D} = 250 \mu A, V_{GS} = 0 V$	40			V
ΔBV_{DSS} ΔT_{J}	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C		36		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 32V, V_{GS} = 0V$			1	μA
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±10	μA
On Chara	cteristics		r			
V _{GS(th)}	Gate to Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 250μA	1.0	1.8	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_{.1}}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\mu$ A, referenced to 25°C		-6.0		mV/°C
0		V _{GS} = 10V, I _D = 17.6A		6.3	7.0	
~	Statia Drain ta Sauraa On Dagiatanga	$V_{GS} = 4.5V, I_D = 14.9A$		7.3	9.0	
DS(on) Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 17.6A,$ T ₁ = 125°C		9.9	11	-mΩ	
9 _{FS}	Forward Transconductance	V _{DS} = 5V, I _D = 17.6A		84		S
-	Characteristics			2665	3545	pF
C _{iss}	Output Capacitance	$V_{DS} = 20V, V_{GS} = 0V,$		325	430	pr pF
C _{oss}	Reverse Transfer Capacitance	f = 1MHz		200	430 295	pr pF
C _{rss} R _g	Gate Resistance	f = 1MHz		2.2	200	Ω
*	g Characteristics			<i>L</i> . <i>L</i>		32
	Turn-On Delay Time			11	20	ns
t _{d(on)} t _r	Rise Time	V _{DD} = 20V, I _D = 17.6A,		6	13	ns
	Turn-Off Delay Time	$-V_{GS} = 10V, R_{GEN} = 6\Omega$		37	60	ns
t _{d(off)} t _f	Fall Time			5	11	ns
Q _q	Total Gate Charge	$V_{GS} = 0V \text{ to } 10V$		47	66	nC
Q _g	Total Gate Charge	$V_{GS} = 0V \text{ to } 5V$ $V_{DD} = 20V,$ $I_D = 17.6A$		25	35	nC
Q _{gs}	Gate to Source Charge	I _D = 17.6A		7		nC
Q _{gd}	Gate to Drain "Miller" Charge			9		nC
	urce Diode Characteristics					
[V _{GS} = 0V, I _S = 2.6A (Note 2)		0.7	1.2	
V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = 17.6A$ (Note 2)		0.8	1.3	V
t _{rr}	Reverse Recovery Time			24	38	ns
	, -	— I _F = 17.6A, di/dt = 100A/μs		15	27	nC

I R_{0,JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0,JC} is guaranteed by design while R_{0,JA} is determined by the user's board design.

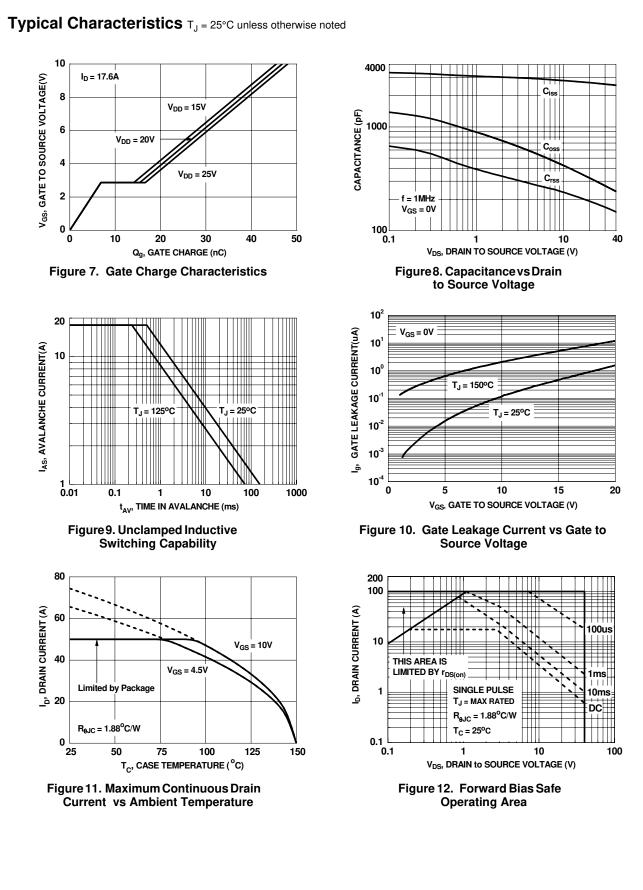
a. 40°C/W when mounted on a 1 $\mbox{in}^2\,\mbox{pad of}\,$ 2 oz copper

b. 62.5°C/W when mounted on a minimum pad.

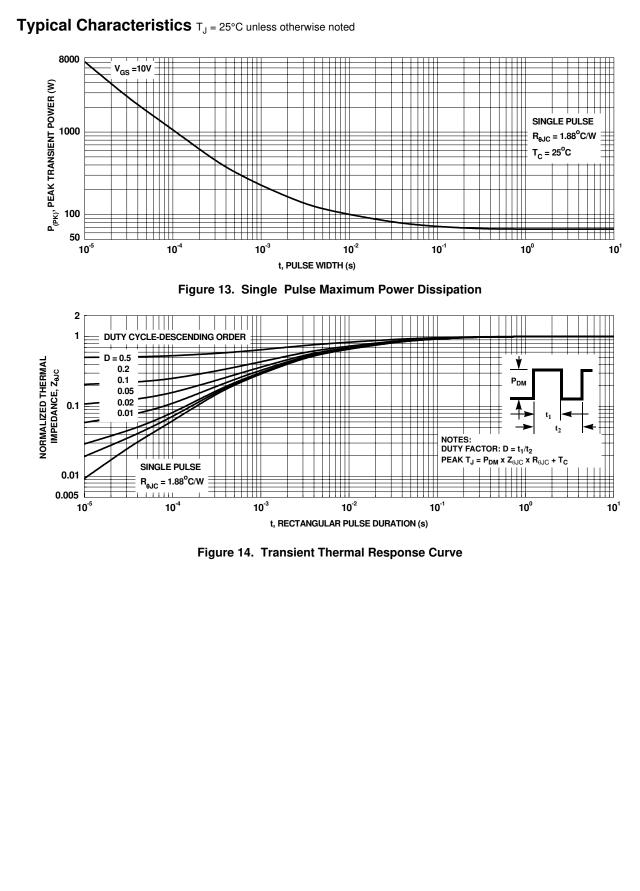
Pulse Test: Pulse Width < 300µs, Duty cycle < 2.0%.
Starting T_J = 25°C, L = 3mH, I_{AS} = 13A, V_{DD} = 40V, V_{GS} = 10V.
The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.



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